

Electro Magnetic Immunity Performance of 10BASE-T1S PHYs

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EMI behavior – P2P vs Multidrop Ethernet

New DPI distortion test defined in Open Alliance (OA) TC14

EMI testing differences: DPI vs BCI vs In-Vehicle

Measurements coupled RF noise

New DPI communication test set-up

Correlation between DPI and In-vehicle measurements



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EMI : point-to-point ethernet, full-duplex



- The transmitter impedance + CMC act as a low-pass-filter (LPF)
- The high common-mode RF voltage is attenuated (34 dB @ 1 MHz)
- LV-CMOS technology can be used for the PHY's

Terminated PHY's -> RF noise is effectively filtered out

EMI : Multi-drop ethernet , half duplex



- Multi-drop, half-duplex : one transmitter node, other nodes are receivers
- Requirement for receiver drop nodes : minimum input impedance > 10 k Ω
- Termination resistors at MDI since end-node PHY's can be a receiver node



EMI : Multi-drop ethernet , half duplex

- Drop nodes > 10 k Ω => LPF > 1 MHz => <u>NO ATTENUATION</u> of HV RF voltage
- Due to CMC resonance the voltage at PHY pins even higher then at MDI
 Receiving nodes -> RF noise is NOT filtered out

Resonance of the Common-Mode-Choke at receiving node



Receiving nodes subjected to high-voltage during EMI

Expected EMI interoperability in a car network



multi-node multi-vendor DPI in-vehicle







Single-vendor 2-node testing shows the best-case behavior and multi-vendor , multinode is the worst-case network behavior

2-node DPI test pass does NOT guarantee EMI performance in a vehicle





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OA TC14 EMC Test Specification - DPI distortion test

- Principle of multi-drop networks: no node shall impact the communication of other nodes
- Use 2-node DPI PCB setup for testing the behavior of a PHY in receiving mode with RF injection
- The failure mask is defined such that cumulative effects of multiple nodes are captured



EMC multi-drop test : a receiving node shall never influence the bus

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EMI testing: DPI vs BCI vs In-Vehicle

- Direct Power Injection (DPI) : IC level EMI test on PCB, two DUT's, floating termination represents multidrop network
- Bulk Current Injection (BCI): ECU level EMI test in a network, multiple nodes
- Vehicle test : complete vehicle tested in an EMC chamber







In-Vehicle

DPI

BCI

Source : Zwickau University of Applied Sciences (FTZ)

Correlation: DPI/BCI and In-Vehicle testing

- Dr. Körber of the University Zwickau (FTZ) has conducted DPI, BCI and vehicle EMI measurements on different 10BASE-T1S products.
- FTZ observed that PHY's that passed DPI/BCI tests were failing vehicle testing.
- There was **NO GOOD** correlation between DPI/BCI and vehicle testing !

• Measurements were performed on coupled RF noise for DPI/BCI and In-Vehicle

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Measurement of coupled RF noise in DPI/BCI/Vehicles



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How a 2-node setup can be representative for multi-drop network



"Floating" termination emulates drop nodes



Frequency Dependent Unbalanced Coupling Network



10BASE-TIS has high mode conversion modeled reliably with the frequency dependent coupling network

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Simulation: Old DPI setup Vs New DPI setup



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New DPI test and Vehicle measurements

New DPI test covers the worst-case in-vehicle performance

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Summary

DPI distortion test

- -<u>Principle of multidrop networks</u>: receiving nodes must not distort the bus
- -Receiving nodes in a 10BASE-T1S network are subjected to high voltage during EMI
- -A dedicated DPI distortion compliance test is part of the OA TC14 standard to prove the required behavior in all operating use cases including unpowered

DPI communication test

- A new DPI communication test has been developed for better correlation with invehicle networks
- -The updated DPI communication test will be part of OPEN ALLIANCE TC14 standard (pending)

Breakthrough in 10BASE-T1S testing to predict in-vehicle EMI performance

Credits and Thanks

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